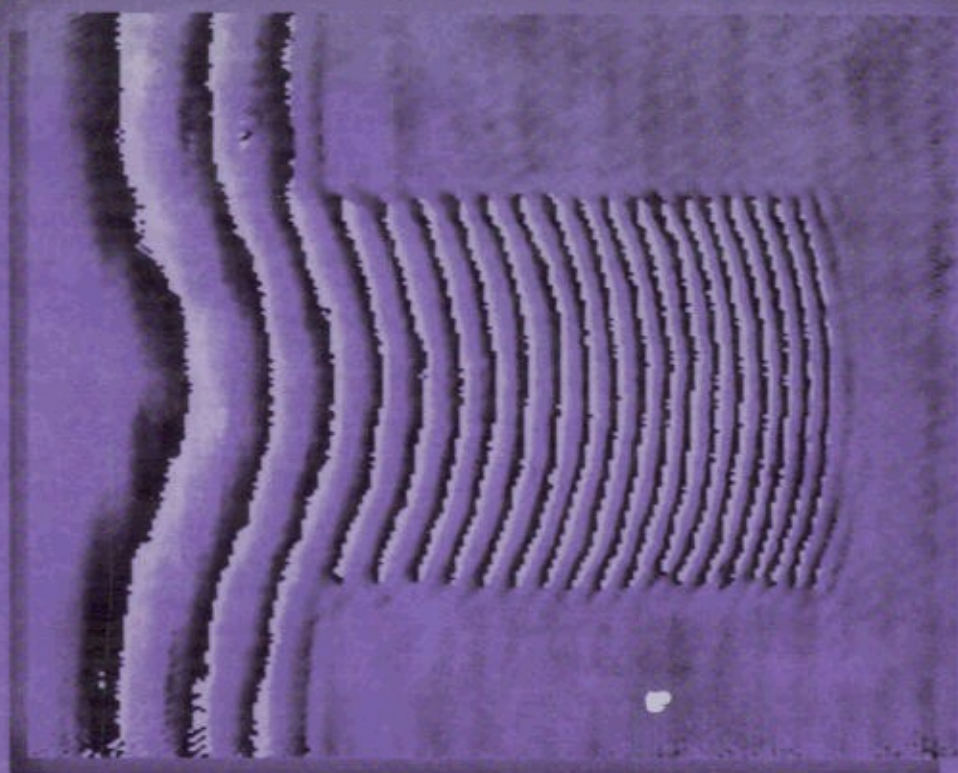


Optical Inspection of Microsystems



edited by

Wolfgang Osten



Taylor & Francis
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